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Form 1449*

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

Atty. Docket No.: 303.648US1

Serial No. 09/484,303

Applicant: Kie Y. Ahn et al.

Filing Date: January 18, 2000

Group: 2823

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| Date Considered 3-22-03 Examiner News *Substitute Disclosure Statement Form (PTO-1449)

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(Use as many sheets as necessary)	Filing Date	January 18, 2000		
OIPE	First Named Inventor	Ahn, Kie		
	Group Art Unit	2825		
JUN 1 1 2002 😭	Examiner Name	Unknown		
Sheet 1 of 1	Attorney Docket No: 00303.648US1			

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EXAMINER Neal Berezny DATE CONSIDERED 3-22-03